Notice of References Cited

Application/Control No.	Applicant(s)/Pater	nt Under	
10/808,552	Reexamination YATSUDA ET AL.		
Examiner	Art Unit		
ANABEL M. TON	2875	Page 1 of 1	

	U.S. PATENT DOCUMENTS				
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2004/0090602	05-2004	Imade, Shinichi	353/102
	В	US-			
	С	US-			
	D	US-			
	Е	US-			
	F	US-			
	G	US-			
	Н	US-			
		US-			
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FOREIGN PATENT DOCUMENTS

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	N					
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